## Notice of References Cited Application/Control No. 10/587,281 Applicant(s)/Patent Under Reexamination HAYASHI ET AL. Examiner Hai Vo Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2007/0160810	07-2007	Hayashi et al.	428/158
*	В	US-2006/0251871	11-2006	Masuda et al.	428/209
*	С	US-2006/0154010	07-2006	Oyama, Shinro	428/036.9
*	D	US-2006/0141159	06-2006	Okuda et al.	427/331
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	Ν	WO 2005003866 A1	01-2005	World Intellect	OYAMA, SHINRO	
*	0	WO 2004108322 A1	12-2004	World Intellect	REISSENWEBER, FRANK	
*	Р	JP 2005200693 A	07-2005	Japan	HAYASHI et al.	
*	α	JP 2004265844 A	09-2004	Japan	HAGA et al.	
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.